

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under	
	09/976,490	Reexamination DORSEY, MICHAEL C.	
	Examiner	Art Unit	
	John P Trimmings	2133	Page 1 of 1

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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

